1. Record Nr. UNISA996391408203316

Titolo	By the King. A proclamation commanding popish recusants to repair to their own dwellings, and not afterwards to come to court, or within ten miles of London, without speciall licence: and for disarming of them, as the law requireth [[electronic resource]]
Pubbl/distr/stampa	Imprinted at London, : by Robert Barker, printer to the Kings most excellent Majestie : and by the assignes of John Bill, 1640
Descrizione fisica	1 sheet ([1] p.)
Altri autori (Persone)	Charles, King of England, <1600-1649.>
Soggetti	Broadsides - England Catholics - Legal status, laws, etc - England
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Note generali	Dated at end: Given at the court at Whitehall the eleventh day of November, in the sixteenth yeer of His Majesties reign. Steele notation: Arms 23; extraordinary of His. Reproduction of original in the British Library.
Sommario/riassunto	eebo-0018

2. Record Nr. UNISALENTO991002839809707536

Autore	Smith, Eric A.
Titolo	Active Server Pages / Smith Eric A.
Pubbl/distr/stampa	Milano : Tecniche nuove, c 2000
ISBN	8848111246
Descrizione fisica	xvi, 652 p. : ill. ; 24 cm
Collana	Internet news. I Manuali
Disciplina	005.276
Soggetti	Web sites Web servers - Computer programs Active server pages
Lingua di pubblicazione	Italiano
Formato	Materiale a stampa
Livello bibliografico	Monografia
Note generali	Tit. orig. : Active Server Pages Bible Includes index

3. Record Nr. UNINA9911019779303321

Titolo	Methods II / / edited by S. Amelinckx ... [et al.]
Pubbl/distr/stampa	Weinheim, : VCH, 1997
ISBN	9786611764654 9781281764652 1281764655 9783527620524 3527620524 9783527620531 3527620532
Descrizione fisica	1 online resource (509 p.)
Collana	Handbook of microscopy : applications in materials science, solid-state physics, and chemistry ; ; [v. 2]
Altri autori (Persone)	AmelinckxS
Disciplina	502.82 502/.8/2
Soggetti	Microscopy Materials - Microscopy
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Note generali	Description based upon print version of record.
Nota di bibliografia	Includes bibliographical references and index.
Nota di contenuto	Handbook of Microscopy, Applications in Materials Science , Solid-state Physics and Chemistry; Contents; IV Electron Microscopy; 2 Scanning Beam Methods; 2.1 Scanning Reflection Electron Microscopy; 2.1.1 Introduction; 2.1.2 Instrumentation; 2.1.3 Performance; 2.1.4 Modes of Operation; 2.1.4.1 Secondary Electron Imaging; 2.1.4.2 Backscattered Electrons; 2.1.4.3 Special Techniques; 2.1.5 Conclusions; 2.1.6 References; 2.2 Scanning Transmission Electron Microscopy; 2.2.1 Introduction; 2.2.2 Scanning Transmission Electron Microscopy Imaging Modes 2.2.3 Scanning Transmission Electron Microscopy Theory2.2.4 Inelastic Scattering and Secondary Radiations; 2.2.5 Convergent-Beam and Nanodiffraction; 2.2.6 Coherent Nanodiffraction, Electron Holography, Ptychology; 2.2.7 Holography; 2.2.8 STEM Instrumentation; 2.2.9 Applications of Scanning Transmission Electron Microscopy; 2.2.10 References; 2.3 Scanning Transmission Electron Microscopy: Z

Contrast; 2.3.1 Introduction; 2.3.2 Incoherent Imaging with Elastically Scattered Electrons; 2.3.3 Incoherent Imaging with Thermally Scattered Electrons
2.3.4 Incoherent Imaging using Inelastically Scattered Electrons2.3.5 Probe Channeling; 2.3.6 Applications to Materials Research; 2.3.6.1 Semiconductors; 2.3.6.2 Ceramics; 2.3.6.3 Nanocrystalline Materials; 2.3.7 References; 2.4 Scanning Auger Microscopy (SAM) and Imaging X-Ray Photoelectron Microscopy (XPS); 2.4.1 Introduction; 2.4.2 Basic Principles of Auger Electron Spectroscopy (AES) and X-Ray Photoelectron Spectroscopy (XPS); 2.4.2.1 Auger Electron Spectroscopy (AES); 2.4.2.2 X-Ray Photoelectron Spectroscopy (XPS); 2.4.2.3 Quantitative Analysis in AES and XPS
2.4.3 Scanning Auger Microscopy (SAM) and Imaging XPS2.4.3.1 Basic Principles of Imaging; 2.4.3.2 General Aspects of Analyzers; 2.4.3.3 Energy Resolution of Deflecting Electrostatic Analyzers; 2.4.3.4 Cylindrical Mirror Analyzer (CMA) versus the Concentric Hemispherical Analyzer (CHA); 2.4.3.5 Imaging Techniques; 2.4.3.6 Magnetic Fields in Imaging XPS; 2.4.4 Characteristics of Scanning Auger Microscopy Images; 2.4.4.1 General Aspects; 2.4.4.2 Background Slope Effects; 2.4.4.3 Substrate Backscattering Effects; 2.4.4.4 Topographic Effects; 2.4.4.5 Beam Current Fluctuation Effects
2.4.4.6 Edge Effects2.4.5 Conclusion; 2.4.6 References; 2.5 Scanning Microanalysis; 2.5.1 Physical Basis of Electron Probe Microanalysis; 2.5.1.1 Electron Interactions with Solids; 2.5.1.2 X-Ray Emission Spectra; 2.5.1.3 Characteristic X-Ray Spectra; 2.5.1.4 Soft X-Ray Spectra; 2.5.1.5 X-Ray Continuum; 2.5.1.6 Overview of Methods of Scanning Electron Beam Analysis; 2.5.1.7 Electron Probe X-Ray Microanalyzers; 2.5.1.8 Analytical Electron Microscopes; 2.5.1.9 Multipurpose Electron Probe Analytical Systems; 2.5.1.10 X-Ray Emission Spectrometry; 2.5.1.11 Wavelength-Dispersive Spectrometry 2.5.1.12 Energy-Dispersive Spectrometry

Sommario/riassunto

Comprehensive in coverage, written and edited by leading experts in the field, this Handbook is a definitive, up-to-date reference work. The Volumes Methods I and Methods II detail the physico-chemical basis and capabilities of the various microscopy techniques used in materials science. The Volume Applications illustrates the results obtained by all available methods for the main classes of materials, showing which technique can be successfully applied to a given material in order to obtain the desired information.With the Handbook of Microscopy, scientists and engineers involved in m

4. Record Nr. UNINA9910557436603321

Autore	Tolnai Domonkos
Titolo	Processing and Characterization of Magnesium-Based Materials
Pubbl/distr/stampa	Basel, Switzerland, : MDPI - Multidisciplinary Digital Publishing Institute, 2021
Descrizione fisica	1 online resource (118 p.)
Soggetti	Technology: general issues
Lingua di pubblicazione	Inglese
Formato	Materiale a stampa
Livello bibliografico	Monografia
Sommario/riassunto	Due to their lightweight and high specific strength, Mg-based alloys are considered as substitutes to their heavier counterparts in applications in which corrosion is non-relevant and weight saving is of importance. Furthermore, due to the biocompatibility of Mg, some alloys with controlled corrosion rates are used as degradable implant materials in the medical sector. The typical processing route of Mg parts incorporates a casting step and, subsequently, a thermo-mechanical treatment. In order to achieve the desired macroscopic properties and thus fulfill the service requirements, thorough knowledge of the relationship between the microstructure, the processing steps, and the resulting property profile is necessary. This Special Issue covers in situ and ex situ experimental and computational investigations of the behavior under thermo-mechanical load of Mg-based alloys utilizing modern characterization and simulation techniques. The papers cover investigations on the effect of rare earth additions on the mechanical properties of different Mg alloys, including the effect of long-period stacking-ordered (LPSO) structures, and the experimental and computational investigation of the effect of different processing routes.